## Notice of References Cited Application/Control No. 10/518,031 Examiner Ellen Kim Applicant(s)/Patent Under Reexamination MILLER ET AL. Art Unit Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,127,078	06-1992	Terry et al.	385/116
*	В	US-6,418,267	07-2002	Lowry, Brian C.	385/147
*	С	US-6,817,746	11-2004	Steiner et al.	362/556
*	D	US-6,850,671	02-2005	Carnevale et al.	385/39
*	E	US-4,379,409	04-1983	Primbsch et al.	73/643
*	F	US-6,249,381	06-2001	Suganuma, Hiroshi	359/618
*	G	US-5,337,325	08-1994	Hwang, Cherng-Jia	372/36
*	Н	US-6,011,885	01-2000	Dempewolf et al.	385/34
*	-	US-4,630,923	12-1986	Tans et al.	356/301
*	J	US-2005/0180706	08-2005	Jones, Michael I.	385/115
*	K	US-5,887,102	03-1999	Mueller et al.	385/115
	L	US-	1		
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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